EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	983	(700/97).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L2	465	(700/99).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L3	580	(700/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L4	177	(700/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L5	113	(700/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L6	256	(700/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L7	98	(700/105).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L8	856	(700/108).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48

EAST Search History

L9	400	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L10	236	(700/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L11	1879	(700/121).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L12	174	(700/128).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L13	239	(700/174).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L14	768	(700/175).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L15	519	(700/178).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L16	160	(700/177).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48

L17	204	(700/21).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L18	657	(700/95).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L19	1372	(700/28).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L20	4090	(438/17).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L21	2507	(438/14).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L22	526	(438/5).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L23	725	(438/10).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L24	175	(438/11).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48

EAST Search History

L25	169	(714/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L26	1238	(714/47).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L27	1112	(714/48).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L28	487	(702/84).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L29	437	(702/81).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L30	191	(702/40).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L31	1741	(702/182).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L32	454	(718/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48

L33	1509	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L34	614	(718/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF·	2007/06/24 23:48
L35	312	(250/586).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L36	132	(324/408).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L37	150	(324/409).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L38	512	(324/719).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L39	769	(324/500).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48
L40	451	(340/657).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/24 23:48

L41	24006	L1 L2 L3 L4 L5 L6 L9 L10 L12 L13 L14 L15 L16 L11 L17 L18 L7 L8 L19 L20 L21 L22 L23 L24 L25 L26 L27 L28 L29 L30 L31 L32 L33 L34 L35 L36 L37 L38 L39 L40	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:53
L42	1853	L41 and ((planning or planner or plan$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48
L43	111	L41 and ((planning or planner or plan$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit$5 or tube) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:53
L44	111	L41 and ((planning or planner or plan$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit$5 or tube) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48
L45	320	L41 and ((planning or planner or plan$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit$5 or tube or electrical) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48

L46	146	L41 and ((planning or planner or plan$5 or scheduling or schedule) same (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit$5 or tube or electrical near (propert$4 or characteristic$2)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48
L47	222	L41 and ((planning or planner or plan$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) same (emission or radiation or sensitivit$5 or tube or electrical near (propert$4 or characteristic$2)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48
L48	1696	L41 and ((planning or planner or plan$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) and (emission or radiation or sensitivit$5 or tube or electrical near (propert$4 or characteristic$2)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48
L49	79	L41 and ((planning or planner or plan$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) with (emission or radiation or sensitivit$5 or tube or electrical near (propert$4 or characteristic$2)) and (wafer or semiconductor or rectile)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48

L50	36	L41 and ((planning or planner or plan$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) with (emission or radiation or sensitivit$5 or tube or electrical near (propert$4 or characteristic$2)) and (wafer or semiconductor or rectile) and (optimal or optimiz$6 or optimis$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48
L51	666	L41 and ((planning or planner or plan$5 or scheduling or schedule) and (testing or test or analyse or analyze or check or examine or experiment or inspect or inspection or measur$3 or sample or sampling or trial or verify)) and (emission or radiation or sensitivit$5 or tube or electrical near (propert$4 or characteristic$2)) and (wafer or semiconductor or rectile) and (optimal or optimiz$6 or optimis$5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48
L52	24006	L41 or L42 or L43 or L44 or L45 or L46 or L47 or L48 or L49 or L50 or L51	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:48
L54	2717	I42 or I43 or I44 or I45 or I46 or I47 or I48 or I49 or I50 or I51	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:55
L55	202	I54 and @pd>"20061214"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/24 23:55

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	465	(700/99).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L2	437	(702/81).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L3	487	(702/84).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L4	614	(718/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L5	580	(700/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L6	177	(700/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L7	113	(700/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L8	98	(700/105).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06

L9	856	(700/108).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L10	400	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L11	236	(700/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L12	1372	(700/28).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L13	394	(712/300).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L14	983	(700/97).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L15	1911	(718/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L16	1509	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06

L17	8987	L1 or L2 or L3 or L4 or L5 or L6 or L7 or L8 or L9 or L10 or L11 or L12 or L13 or L14 or L15 or L16	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/25 00:06
L18	311	L17 and (schedule or path) and (sensitivities or sensitivity or (electrostatic near3 discharge) or overstress or (latch near2 up) or electron or (ion near2 contamination) or (negative near bias))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/25 00:06
L19	165	L17 and (optimal or optimization) with schedule	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/25 00:06
L20	465	(700/99).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L21	437	(702/81).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L22	487	(702/84).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L23	614	(718/103).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L24	580	(700/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06

EAST Search History

L25	177	(700/101).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L26	113	(700/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L27	98	(700/105).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L28	856	(700/108).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L29	400	(700/109).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L30	236	(700/112).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L31	1372	(700/28).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L32	394	(712/300).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06

L33	983	(700/97).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L34	1911	(718/100).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L35	1509	(718/102).CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/06/25 00:06
L36	8987	L20 or L21 or L22 or L23 or L24 or L25 or L26 or L27 or L28 or L29 or L30 or L31 or L32 or L33 or L34 or L35	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/25 00:06
L37	7	(radiation or emission or (flash near2 tube) or tube) same (schedule or plan or planning or scheduling) and (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze) and (wafer or semiconductor or rectile) and L36	US-PGPUB; USPAT	OR	ON	2007/06/25 00:06
L38	99	(schedule or plan or planning or scheduling) same (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze) and (wafer or semiconductor or rectile) and L36	US-PGPUB; USPAT	OR	ON	2007/06/25 00:06

L39	1	floor near (schedule or plan or planning or scheduling) same (optimal or optimization) and model and (testing or test or analyse or check or examine or experiment or inspect or inspection or measure or sample or trial or verify or analyze) and (wafer or semiconductor or rectile) and L36	US-PGPUB; USPAT	OR	ON	2007/06/25 00:06
L40	522	L18 or L19 or L37 or L38 or L39	US-PGPUB; USPAT	OR	ON	2007/06/25 00:09
L41	44	I40 and @pd>"20061211"	US-PGPUB; USPAT	OR	ON	2007/06/25 00:10